

**Search Notes****Application/Control No.**

10/788,667

**Examiner**

Hiep Nguyen

**Applicant(s)/Patent under Reexamination**

FERIANZ ET AL.

**Art Unit**

2816

**SEARCHED**

Class	Subclass	Date	Examiner
327	108	03.28.05	<i>Hiep</i>
	109	—	—
	110	—	—
326	82		
	83		
	86		
	87		
	91	↓	↓

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	03.28.05	<i>Hiep</i>
See attachment		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner